



# Results from the 2012 beam test of the Asian GEM modules

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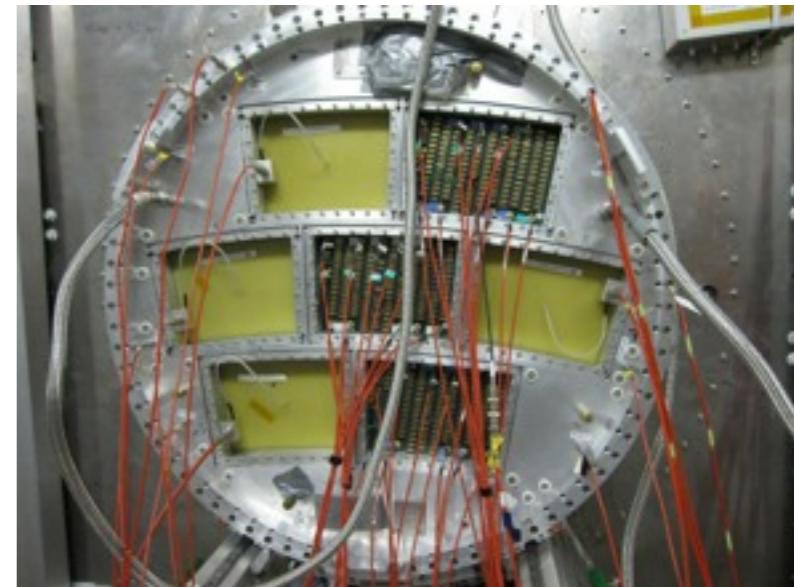
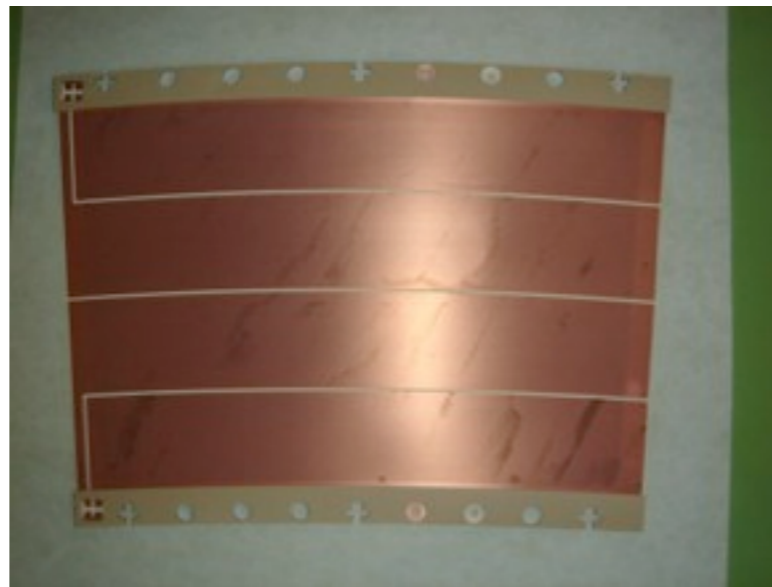
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on behalf of LCTPC-Asia group

ECFA LC2013, May 27-31 @ DESY, Hamburg

# outline

- ❖ **General results**
  - pulse shape
  - hit efficiency
  - spatial resolution
- ❖ **Charge loss issue**
  - gain uniformity
  - discharge
  - cross talk
  - threshold effect
  - MC with real charge loss
- ❖ **summary**



Nov. 19 - Dec. 18, 2012 @ T24, DESY

**Many thanks to the support of DESY and Lund TPC group!**

# Data and Reconstruction

- $B=0T, B=1T$
- z-scan: (2.5cm - 50cm)
- x-scan: (-2cm - 2cm)
- theta-scan: ( $-10^\circ, 10^\circ$ )
- phi: ( $0^\circ, 10^\circ$ )
- different gains, shaping times, threshold

**Analysis Framework: MarlinTPC v01-11**

**Reconstruction flow:**

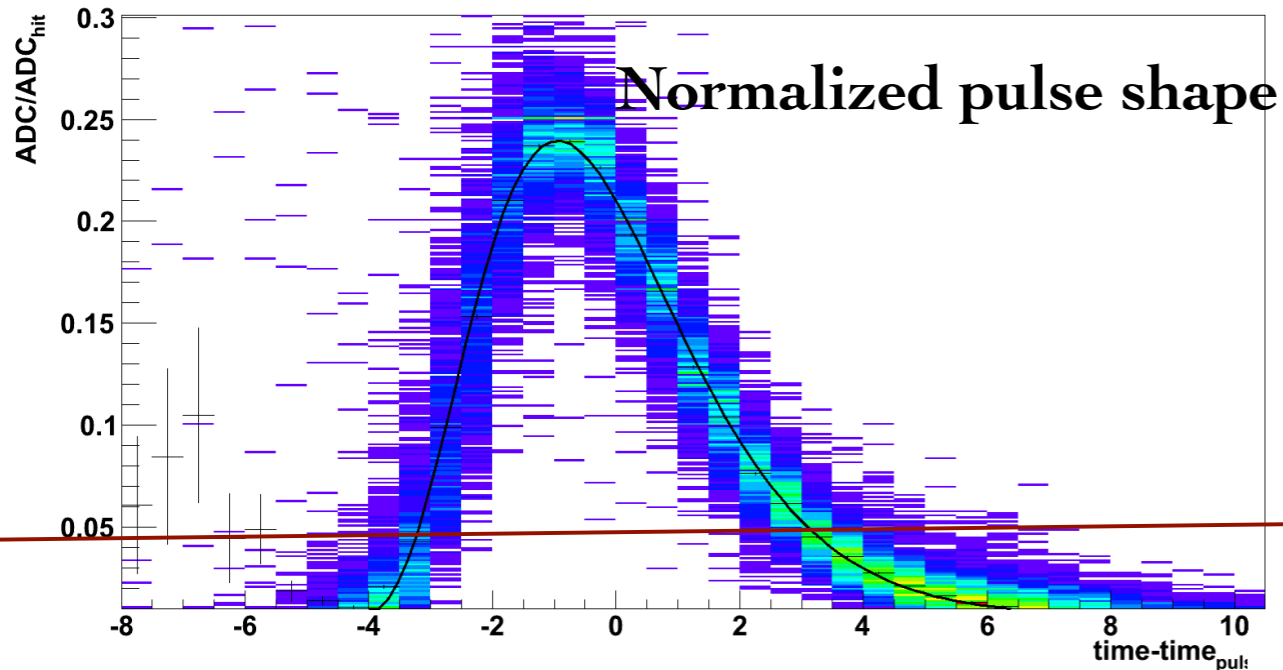
- ▶ pulse finder
- ▶ channel mapping
- ▶ row based hit finder
- ▶ tracking by kalman filter

data available on grid: /grid/ilc/tpc/2012/t24/jgem/rawdata

run information: <http://www-hep.phys.saga-u.ac.jp/ILC-TPC/index.php?Large%20Prototype%201%2FTests%2FBeamTest%202012%2FData%20Taking#s51a2905>

# Pulse shape

pulse example



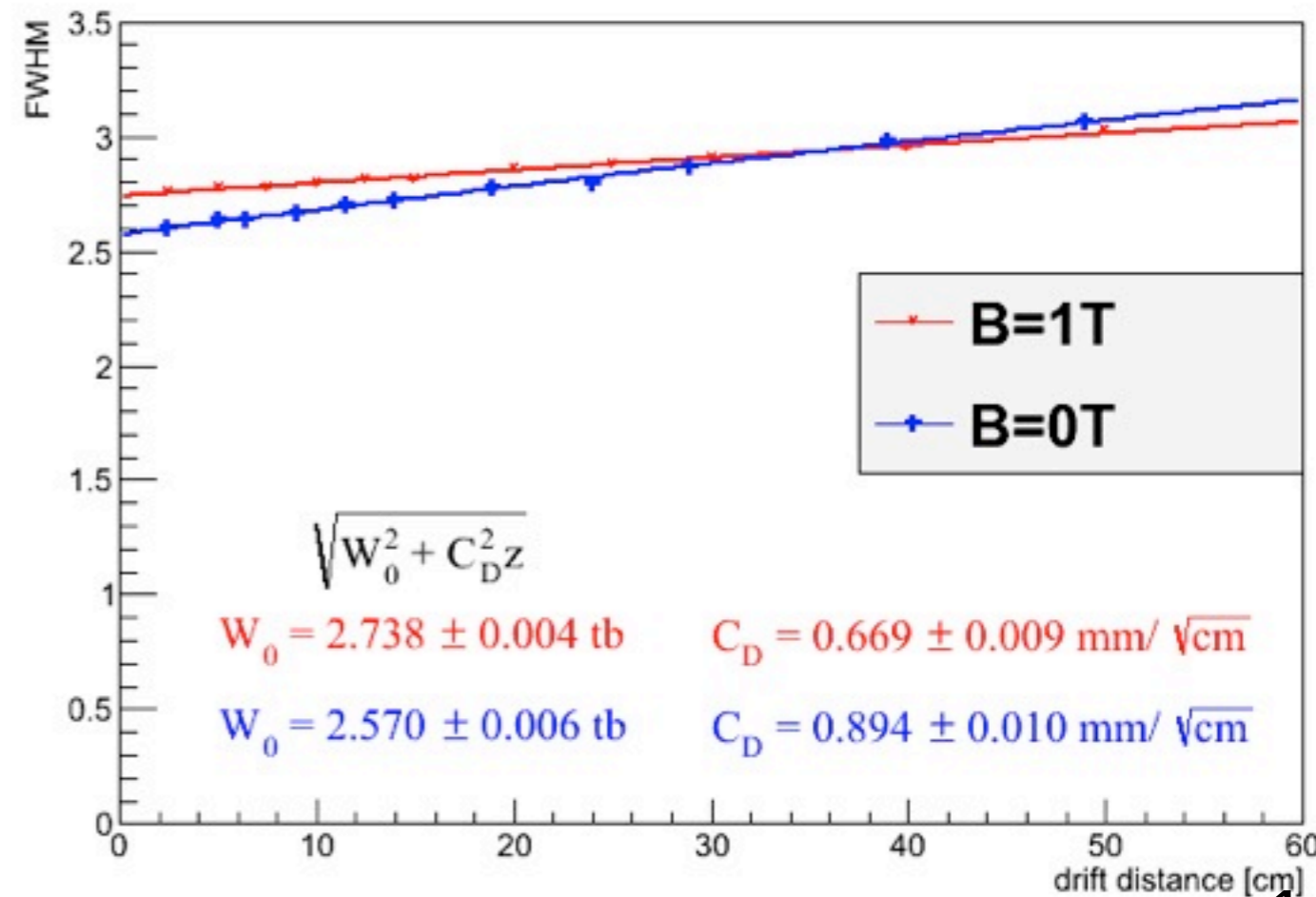
well-understood behavior,  
relative threshold used in  
pulser finder

1 time bin = 50 ns

$$f(x) = A \left( \frac{t - t_0}{\tau} \right)^4 e^{-\frac{t-t_0}{\tau}}$$

$\Gamma$  = Full Width at Half Maximum

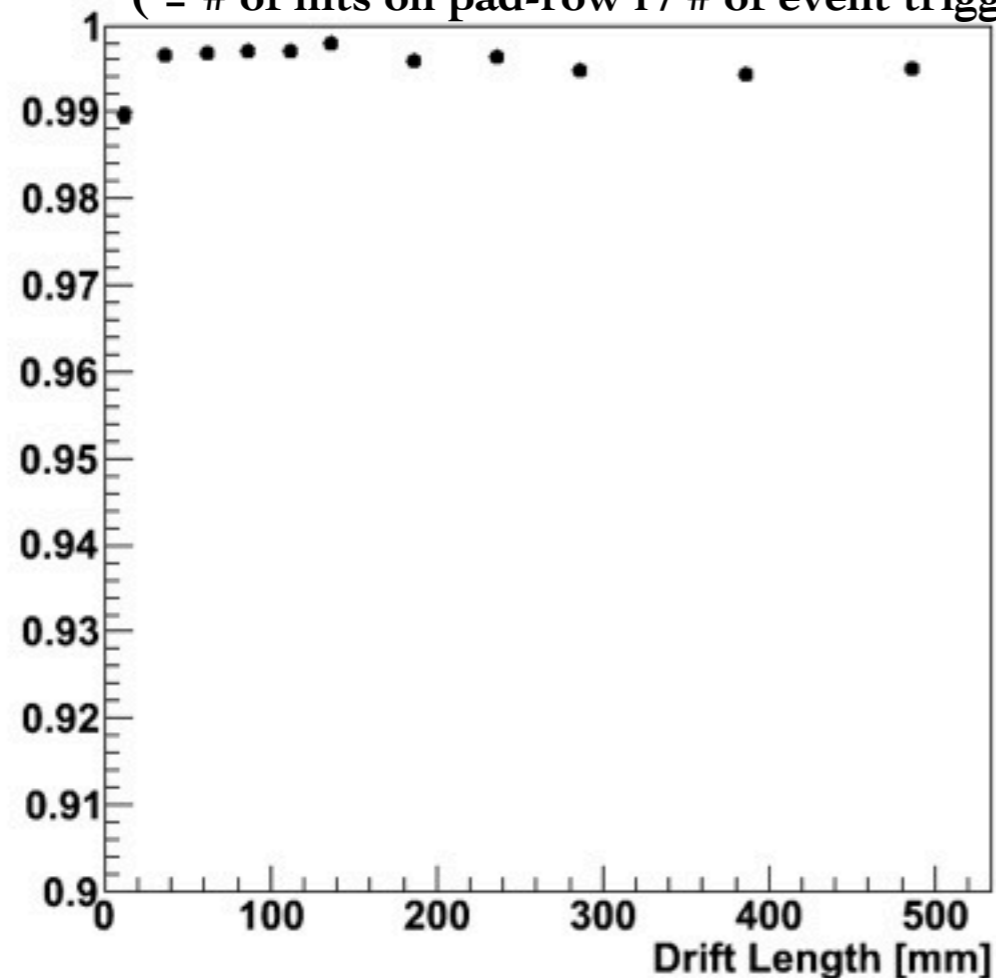
pulse width:  
longitudinal diffusion



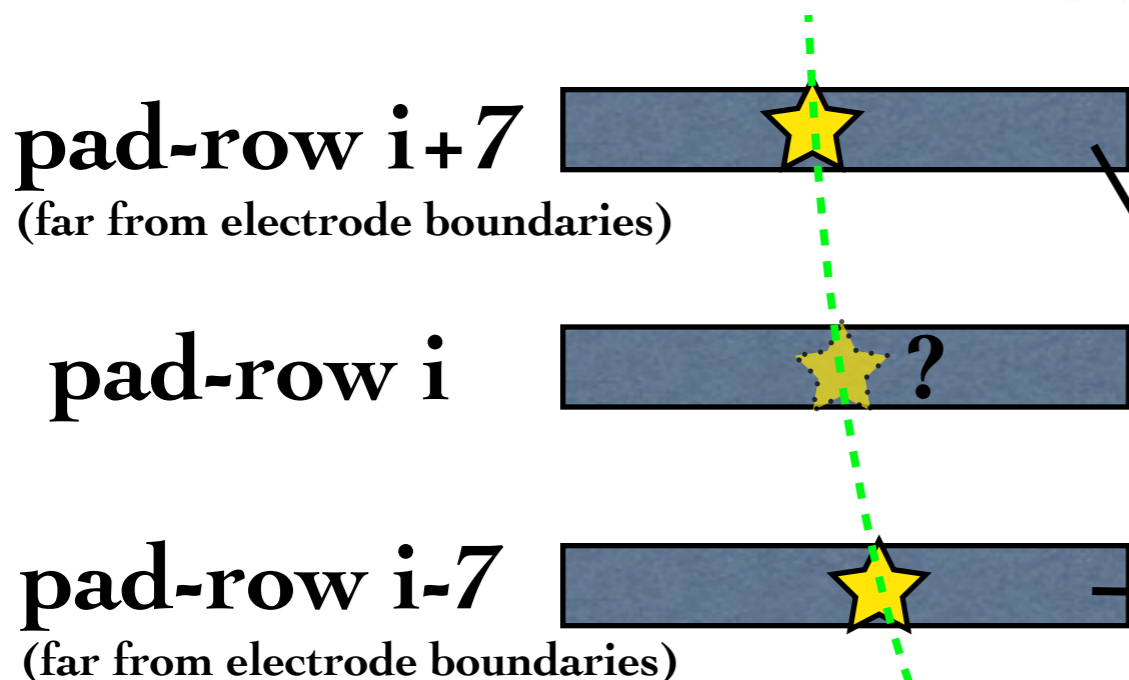
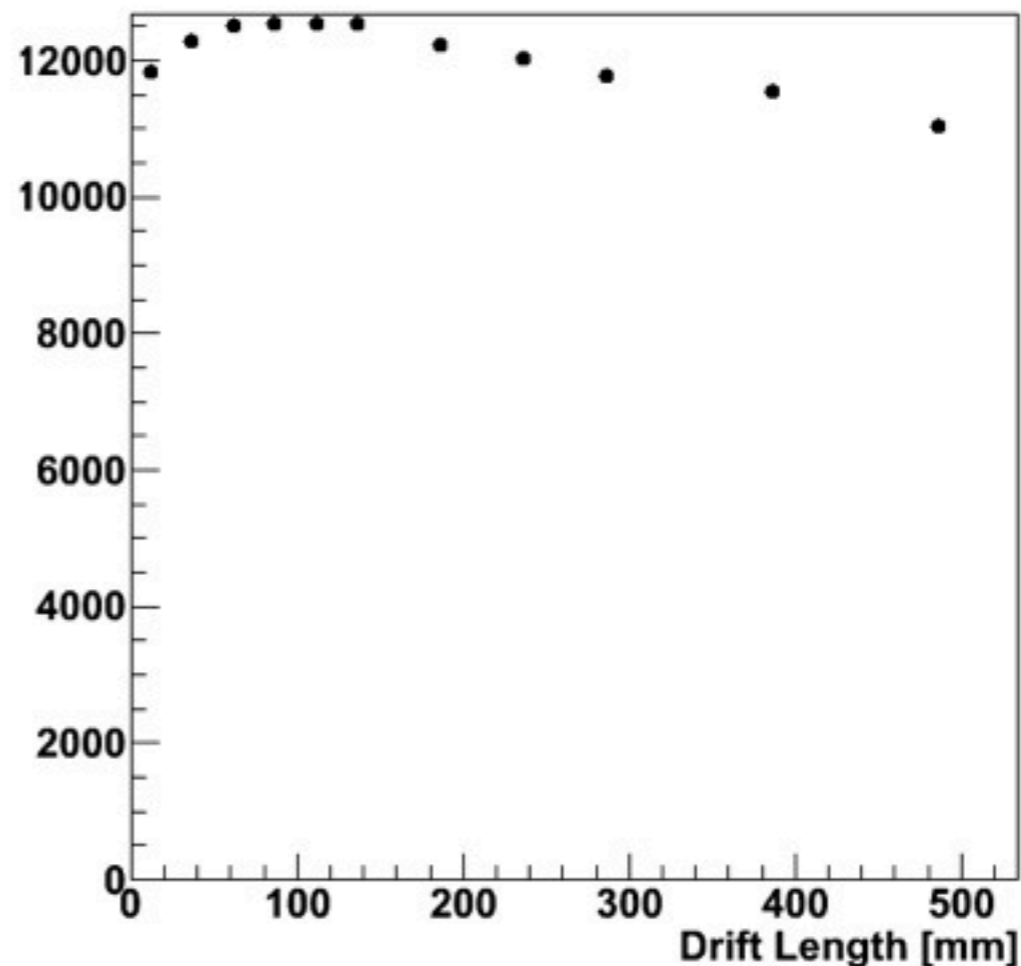
# Hit efficiency

(pad-row 17 of module 3 (center) )

**Hit Efficiency**  
( = # of hits on pad-row  $i$  / # of event triggers )



**# of samples** ( = # of event triggers )

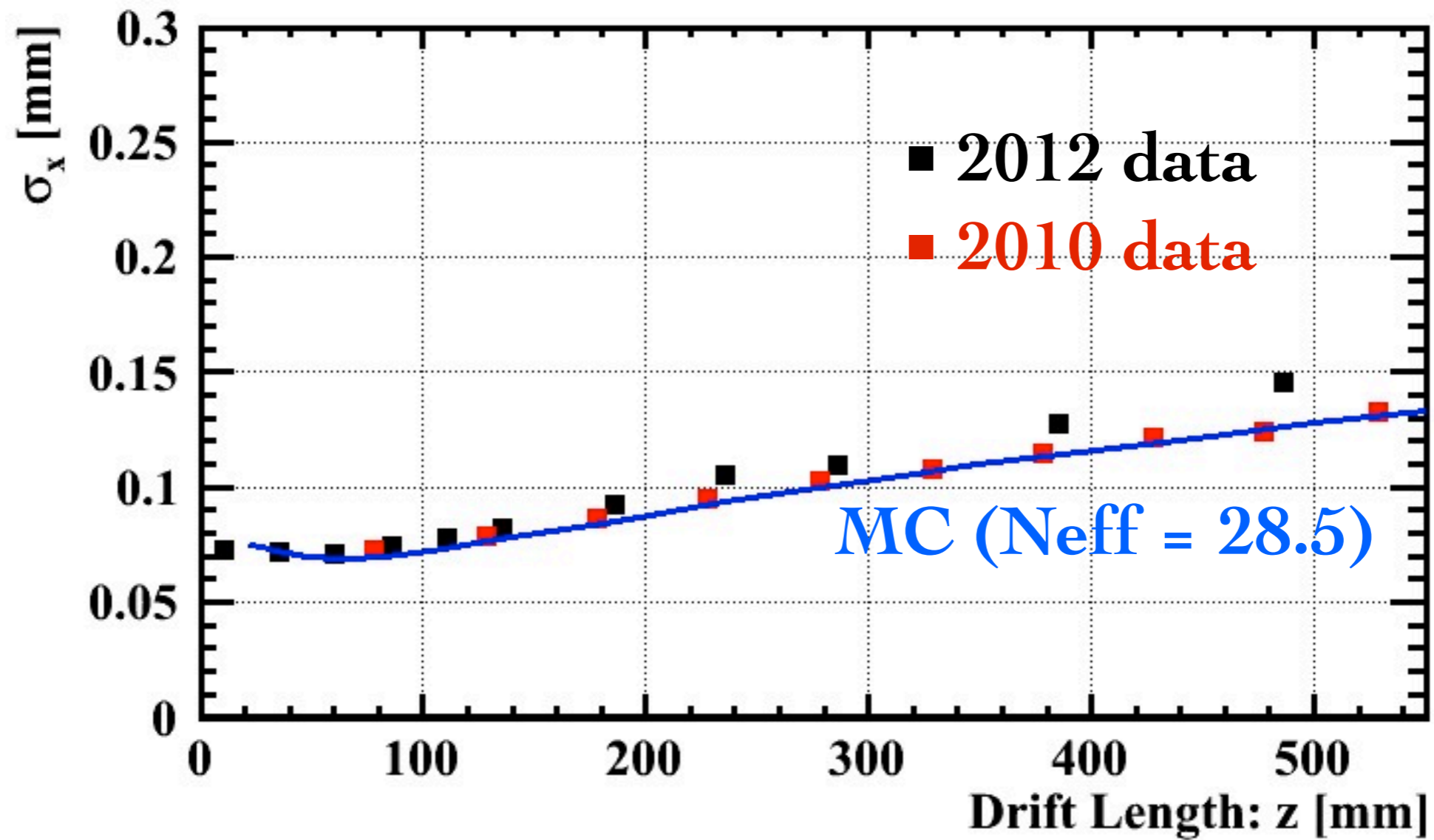


We checked if there is a hit on pad-row  $i$  while requiring hits on both pad-row  $i \pm 7$ .

Used as a event trigger

# xy-resolution

central module, row 17

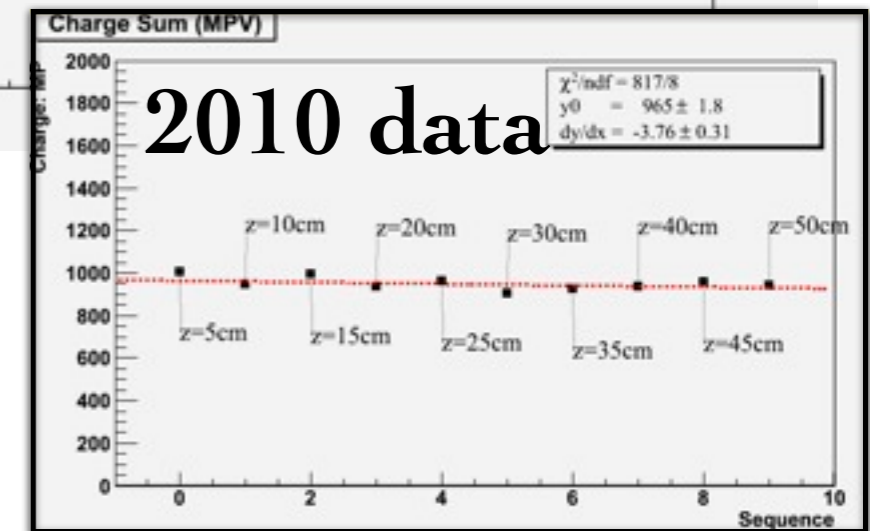
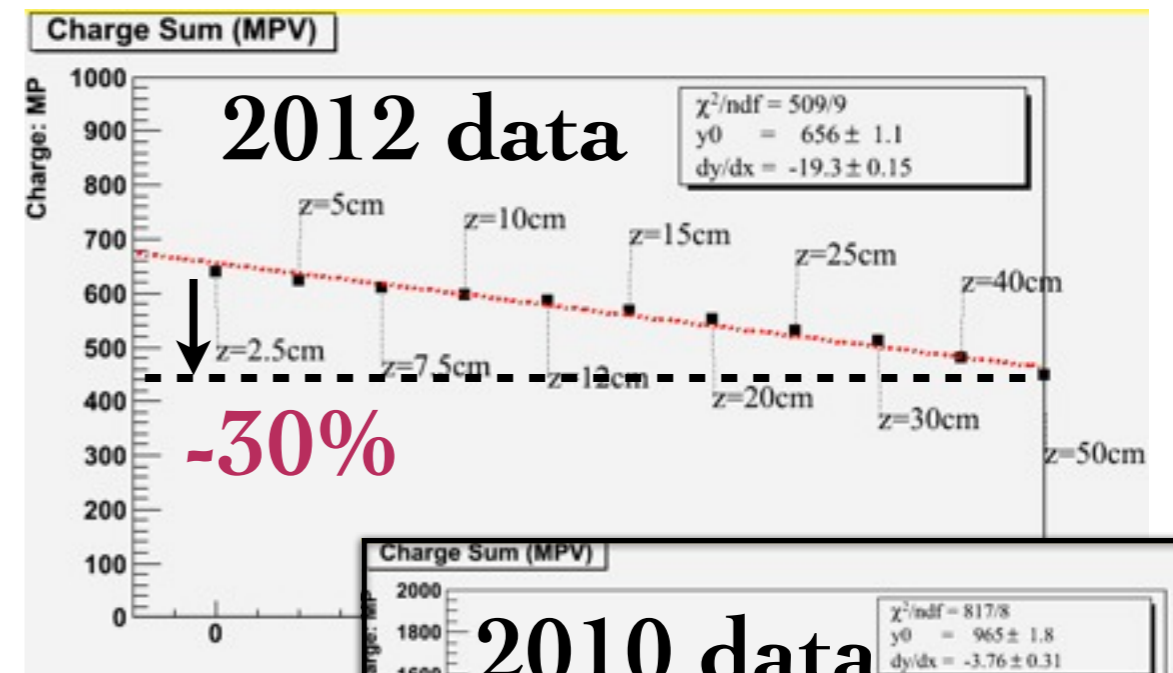


# An issue of charge loss

Apparent charge loss  
as a function of drift length

The loss is too much compared  
to measured oxygen content :  
70ppm which corresponds to  
-10% / 500mm.

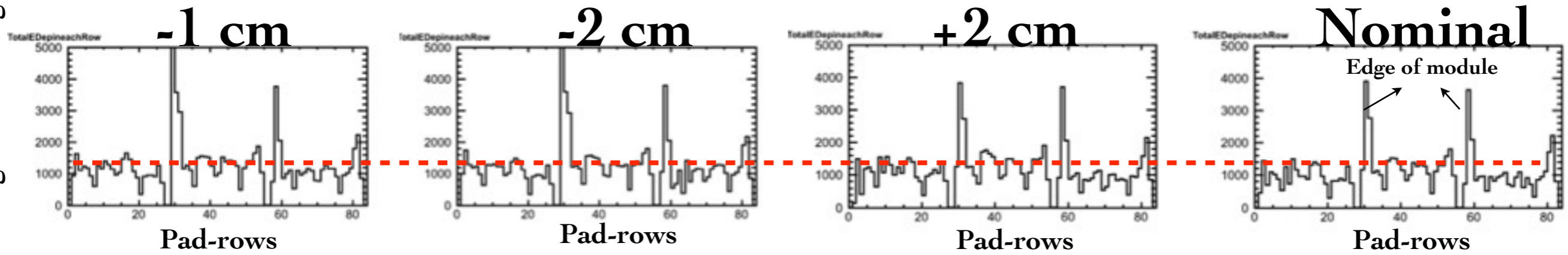
- Gain uniformity?
- Discharge effect?
- Crosstalk?
- Threshold effect?
- Real charge loss?



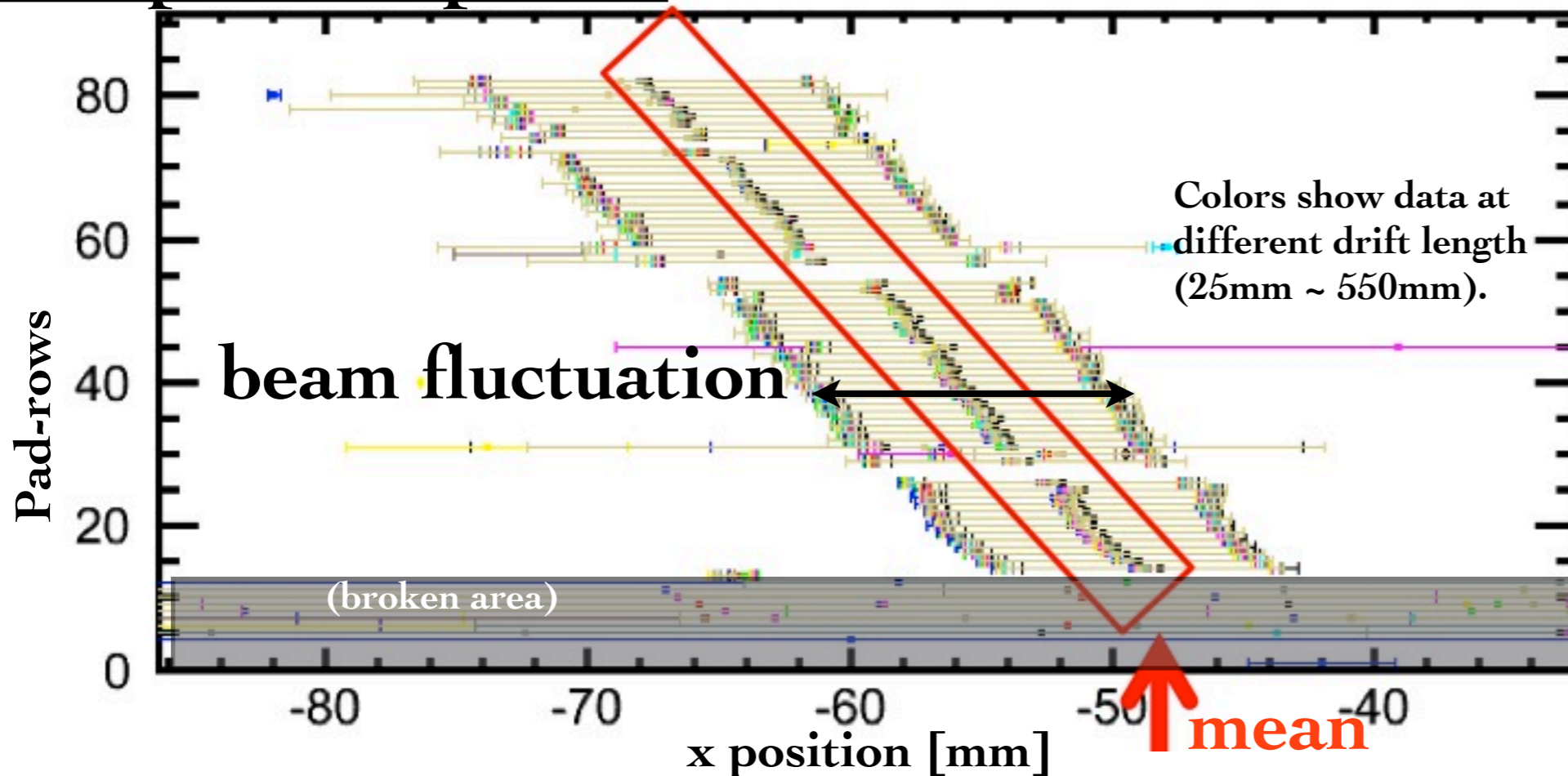
# Gain Uniformity

x-position dependence --> No dependence

Average of hit charge



beam position profile



Within beam fluctuation including difference of drift length, gain should be almost same.

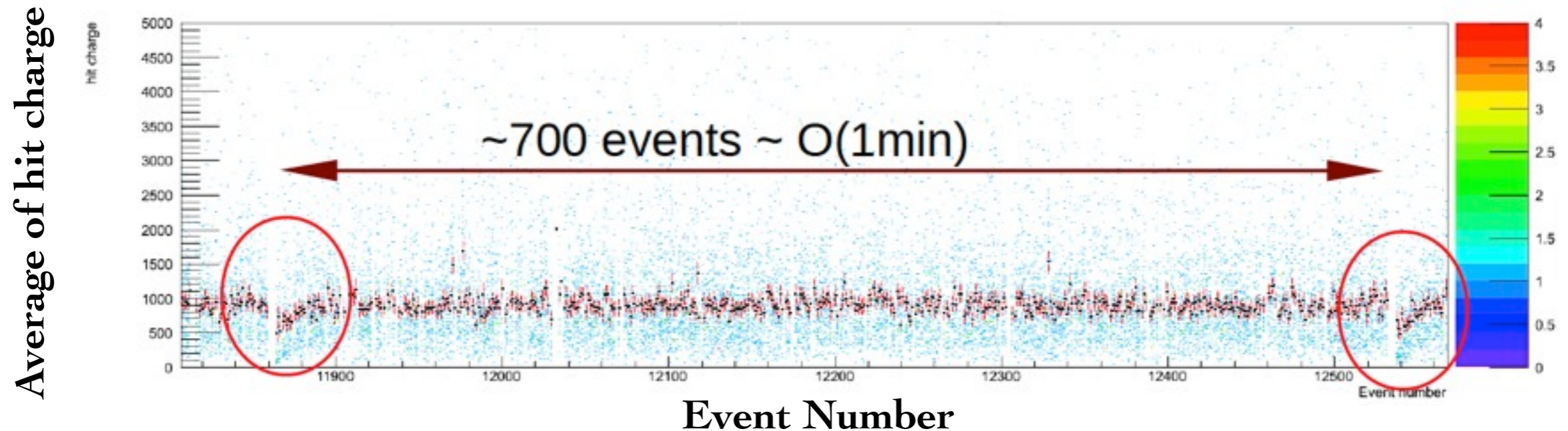
--> We should have same gain at each drift length.

--> Gain variance can not be the cause of the "charge loss".



# Discharge Events

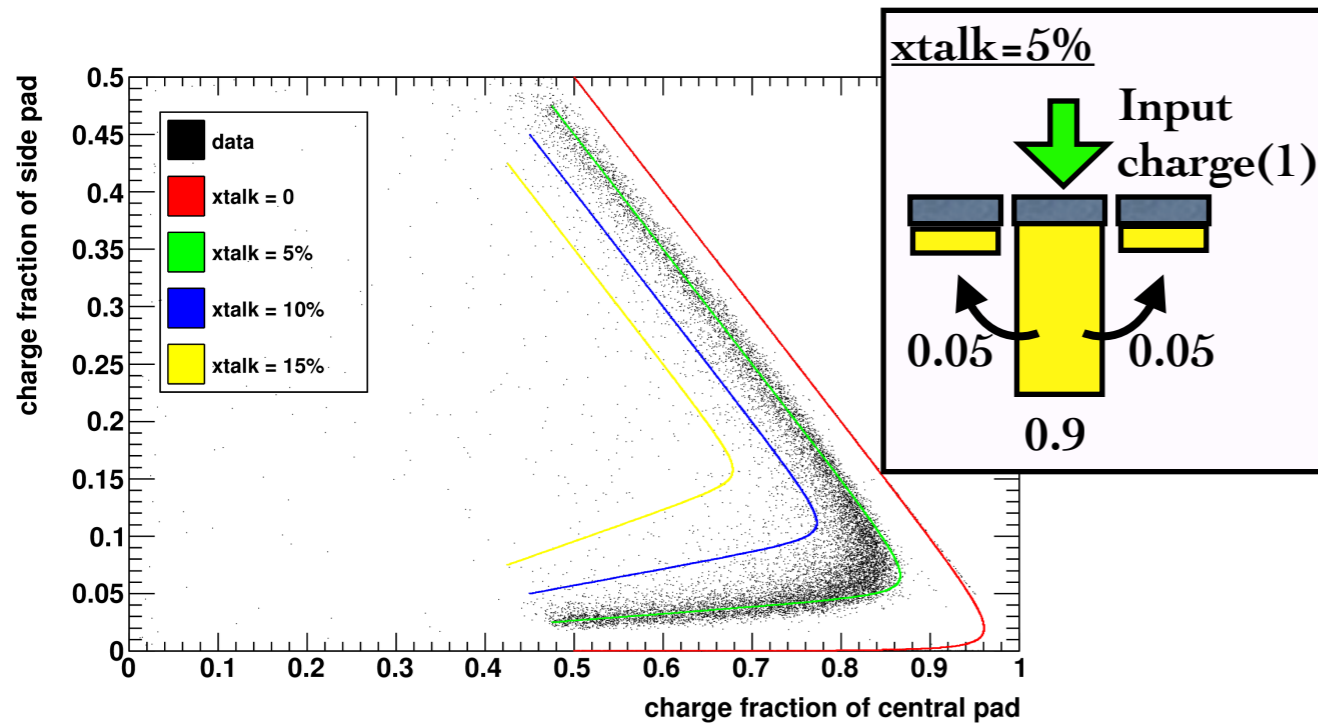
Unfortunately we had some discharges during the beam test. A discharge can be identified as a gain drop.



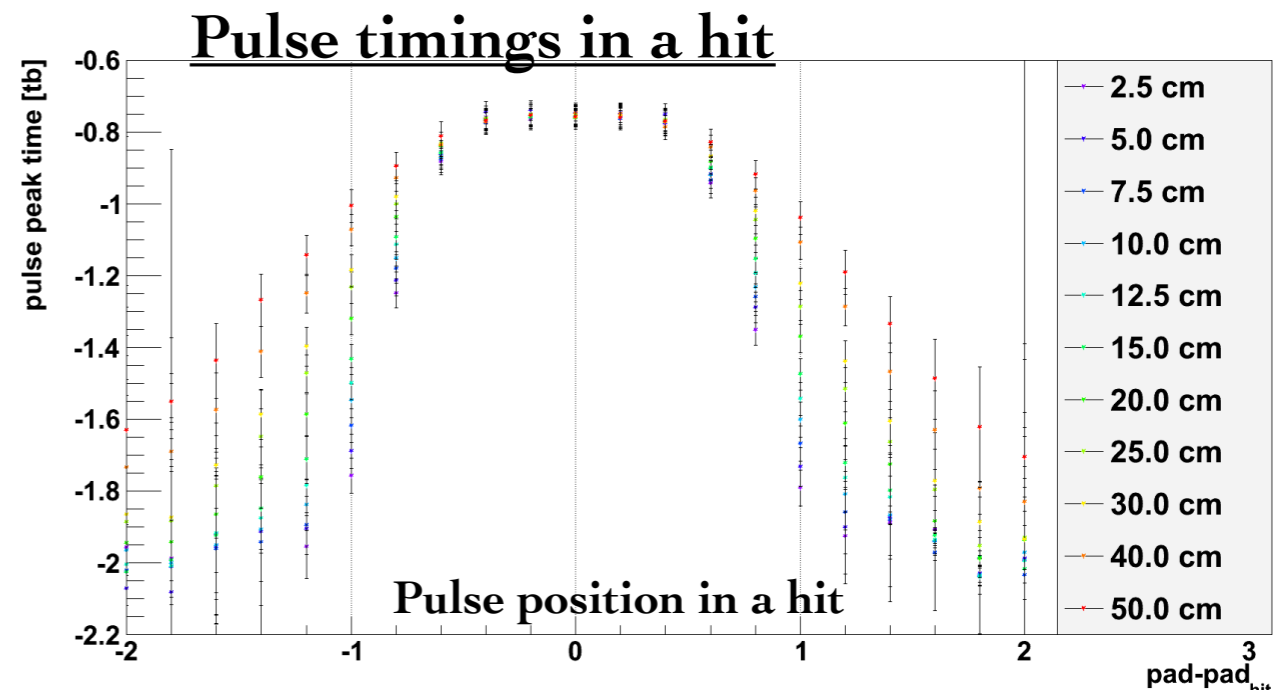
We removed these events from our analysis.

# Cross talk and Induction Signals

Indicating cross talk (5% + 5%)



Indicating induction signals



The pulses around edges come earlier than that of center. --> There seems to be some contribution from induction signals.

We took these effects into a MC simulation and checked the behavior of hit charge as a function of drift length. But we were not able to reproduce the “charge loss”. --> These can not be the cause of the “charge loss”.

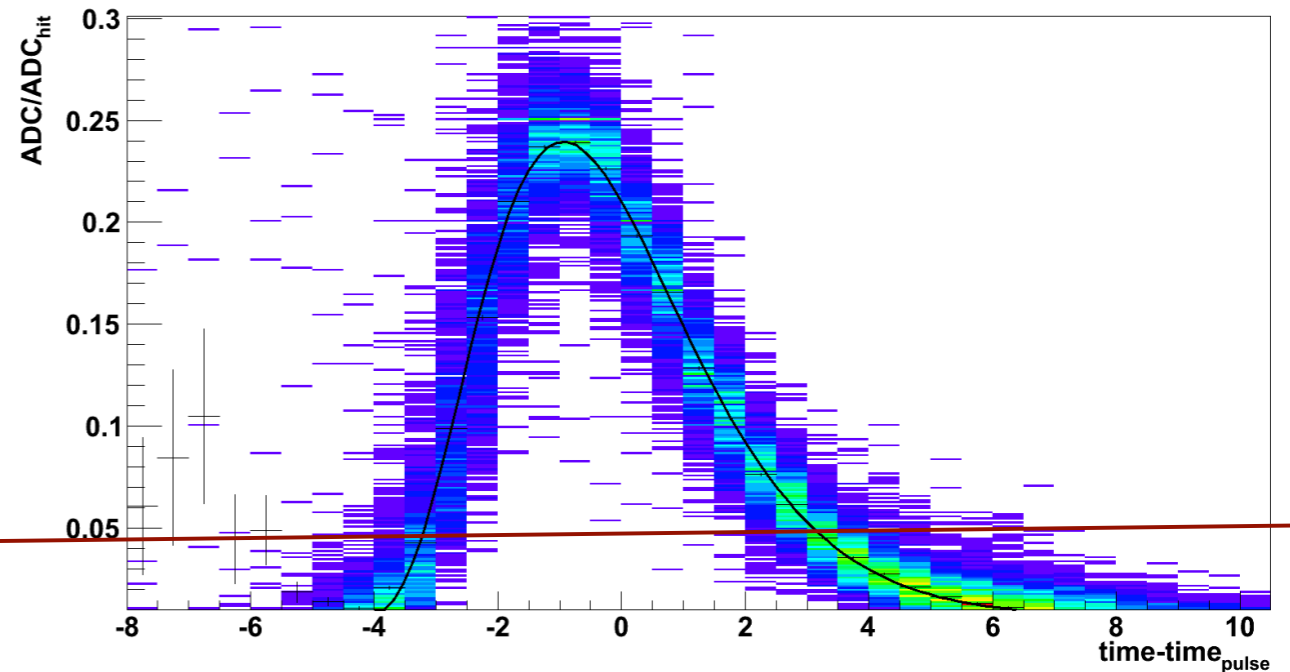
# Threshold Effect (Pulse)

## Normalized pulse shape

In order to cut equally the pulse tail, we introduced thresholds(start/end) being relative to the peak.

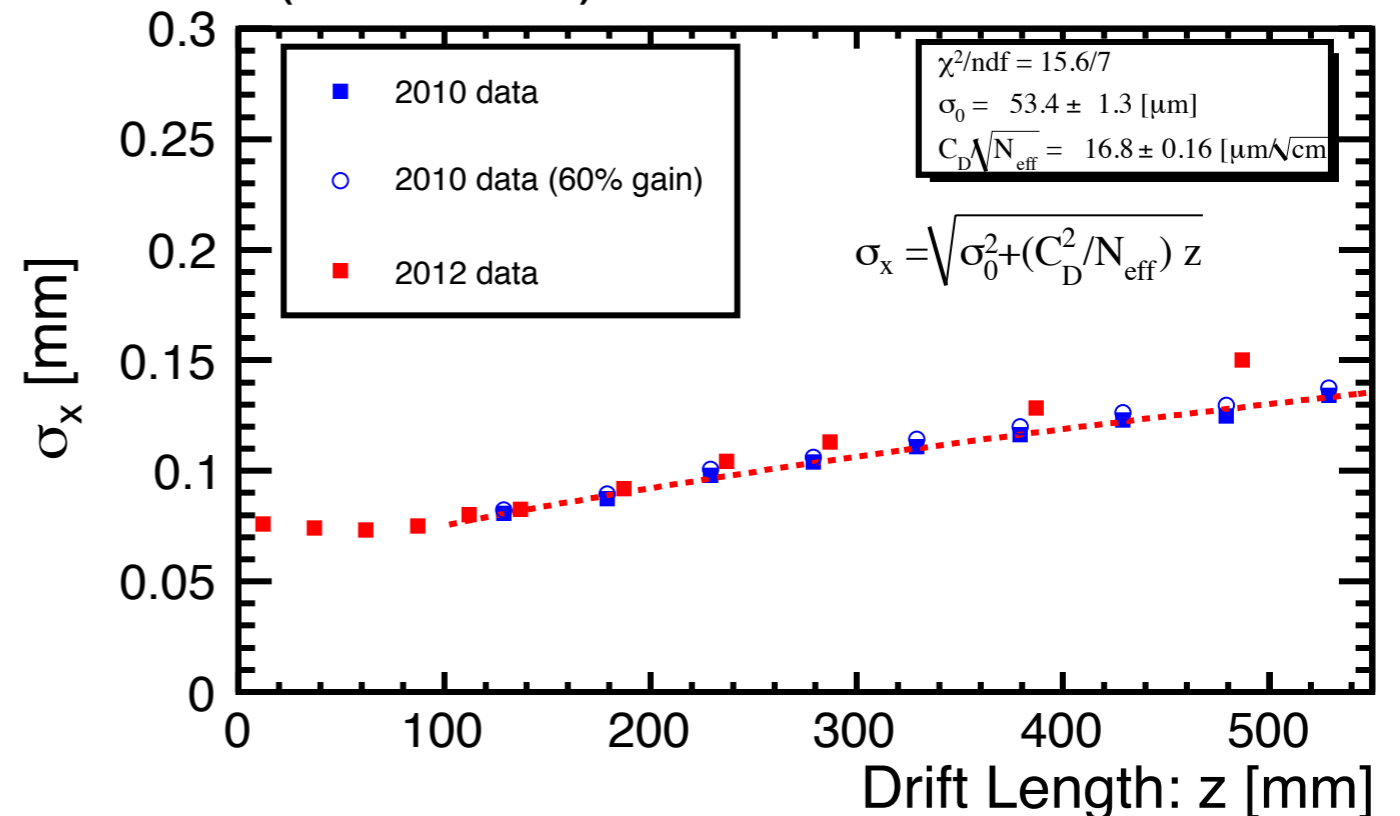
--> No big difference in "charge loss"

pulse example

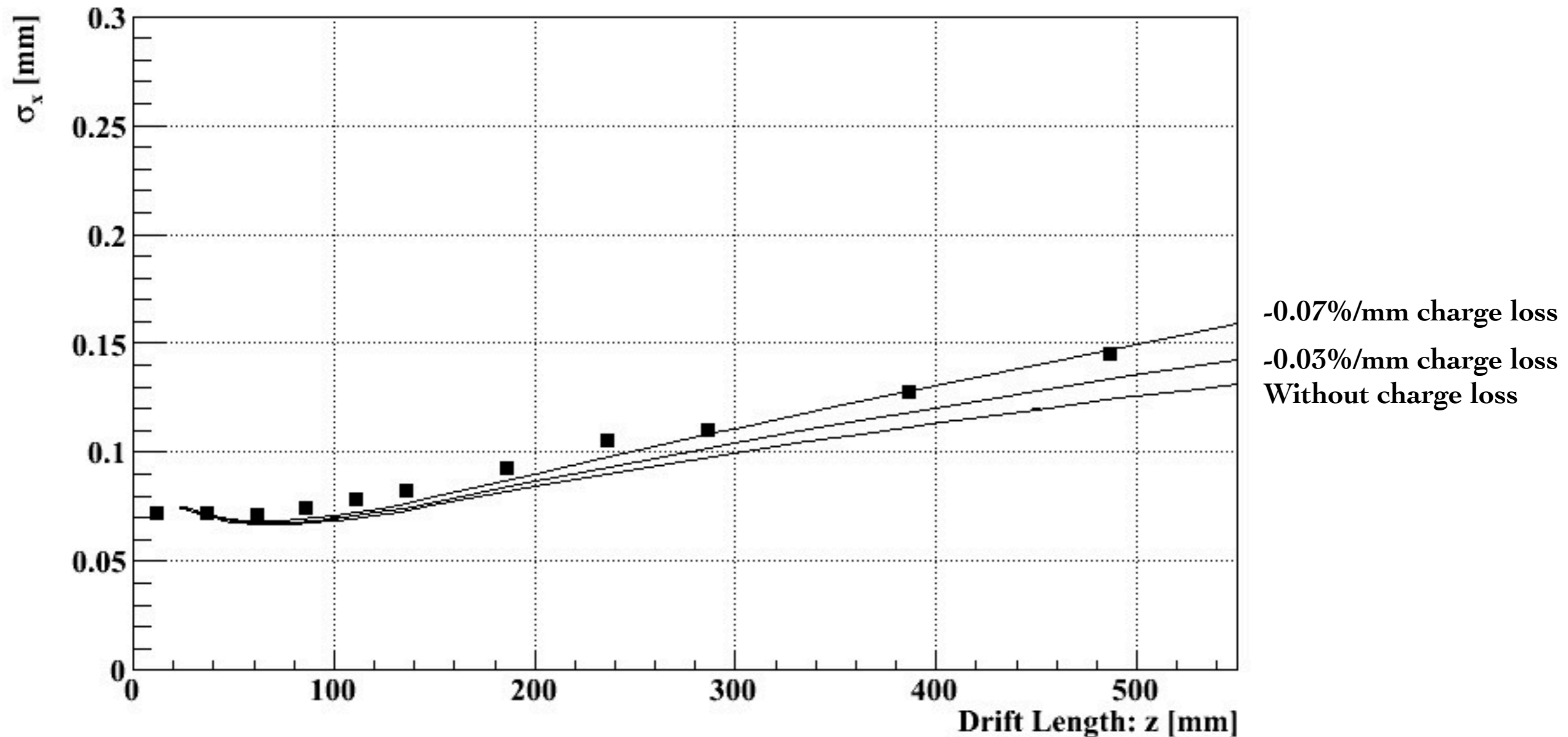


threshold check with  
2010 data: technically  
reduce the gain by 40%

GM Resolutin (Module3 Row17)



# MC with real charge loss



**$N_{\text{eff}} = 28.5$  (consistent with 2010 data)**

**0.07%/mm --> 30% loss at 500 mm**

**--> consistent with charge sum behavior**

# charge loss?

- ✓ - Gain uniformity --> no gain variation
- ✓ - Discharge effect --> removed
- ✓ - Crosstalk, induction signals --> no effect
- ✓ - Threshold effect (pulse/hit reconstruction) --> no change
- ✓ - Neff (spatial resolution) --> consistent with decreasing Neff

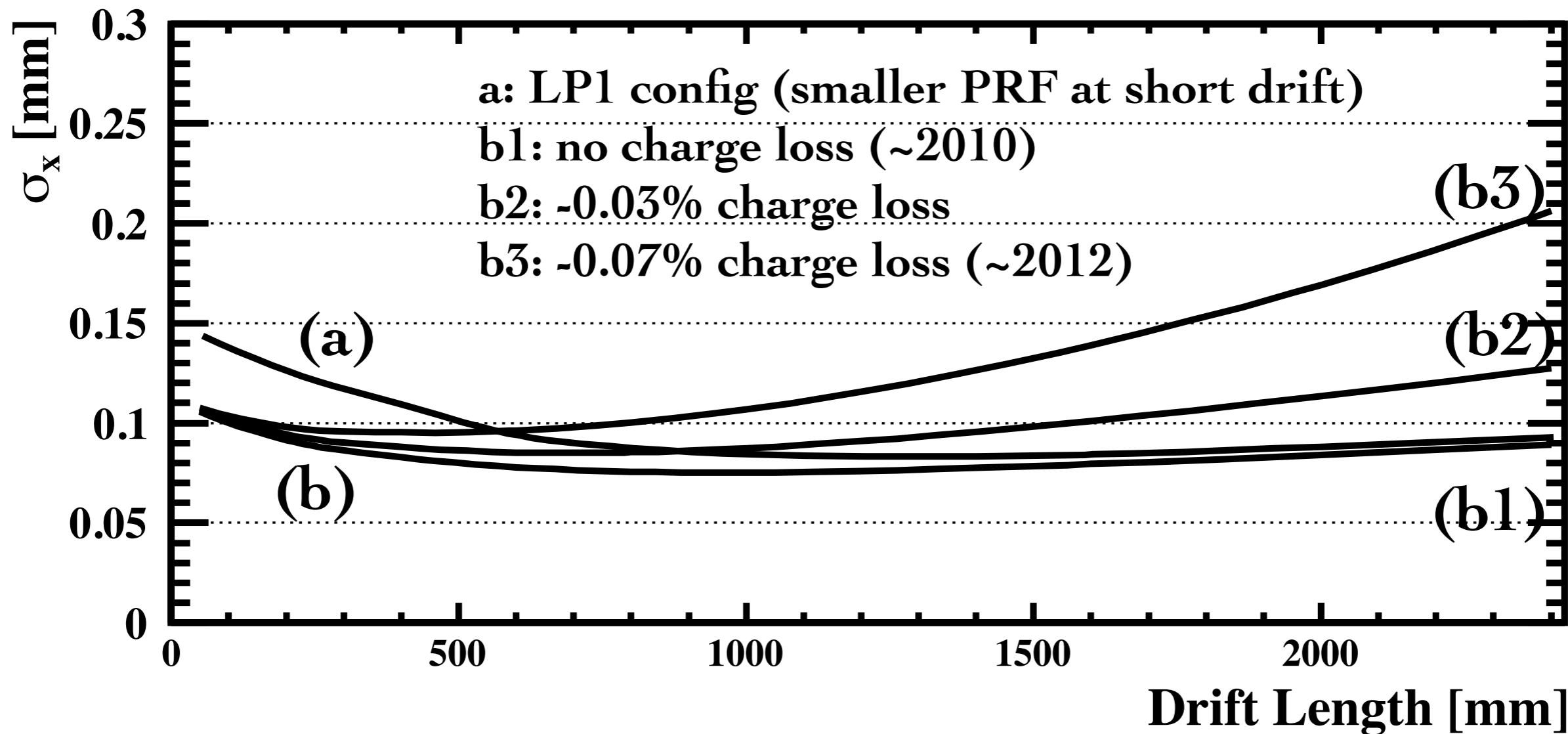
The data supports that we really lost seed electrons.

# Extrapolation to the ILD-TPC (MC)

Ryo's Simulation

Drift length 600mm --> 2400mm

B 1 T --> 3.5 T



gas : Ar-CF4-isoC4H10 (95:3:2) (T2Kgas)  
pad height = 5.26 mm  
pad width = 1.16 mm  
Neff = 28.5  
Cd = 30 microns / sqrt(cm) at 3.5 T  
sigma\_prf = 0.20 mm (a), 0.26 mm (b) at 3.5 T

it is essential to measure  
the key parameters (Neff,  
PRF..) at 3.5 T

# Summary

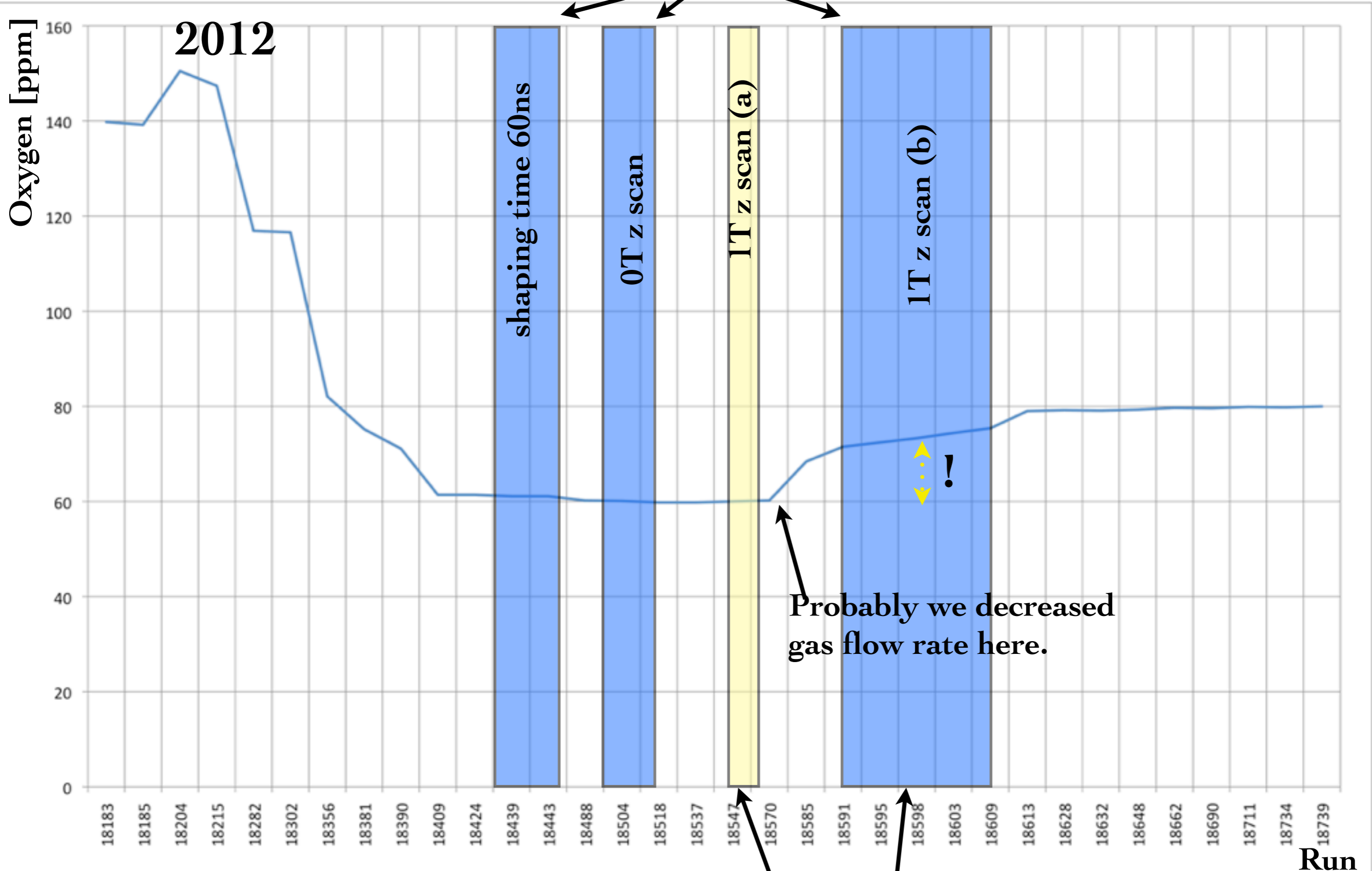
- ❖ lots of data taken during the 2012 beam test:  
generally the Asian GEM is working well, high hit efficiency, longitudinal diffusion, reasonable point resolutions.
- ❖ confirmed gain uniformity, cross talk.
- ❖ discharge need be solved in future module.
- ❖ indicate real charge loss in our test.
- ❖ confirmed resolution of 2010 data which can meet the requirement of ILD-TPC.
- ❖ further analyses are still going on.

**Back up**



# Oxygen data

# The runs we checked so far.

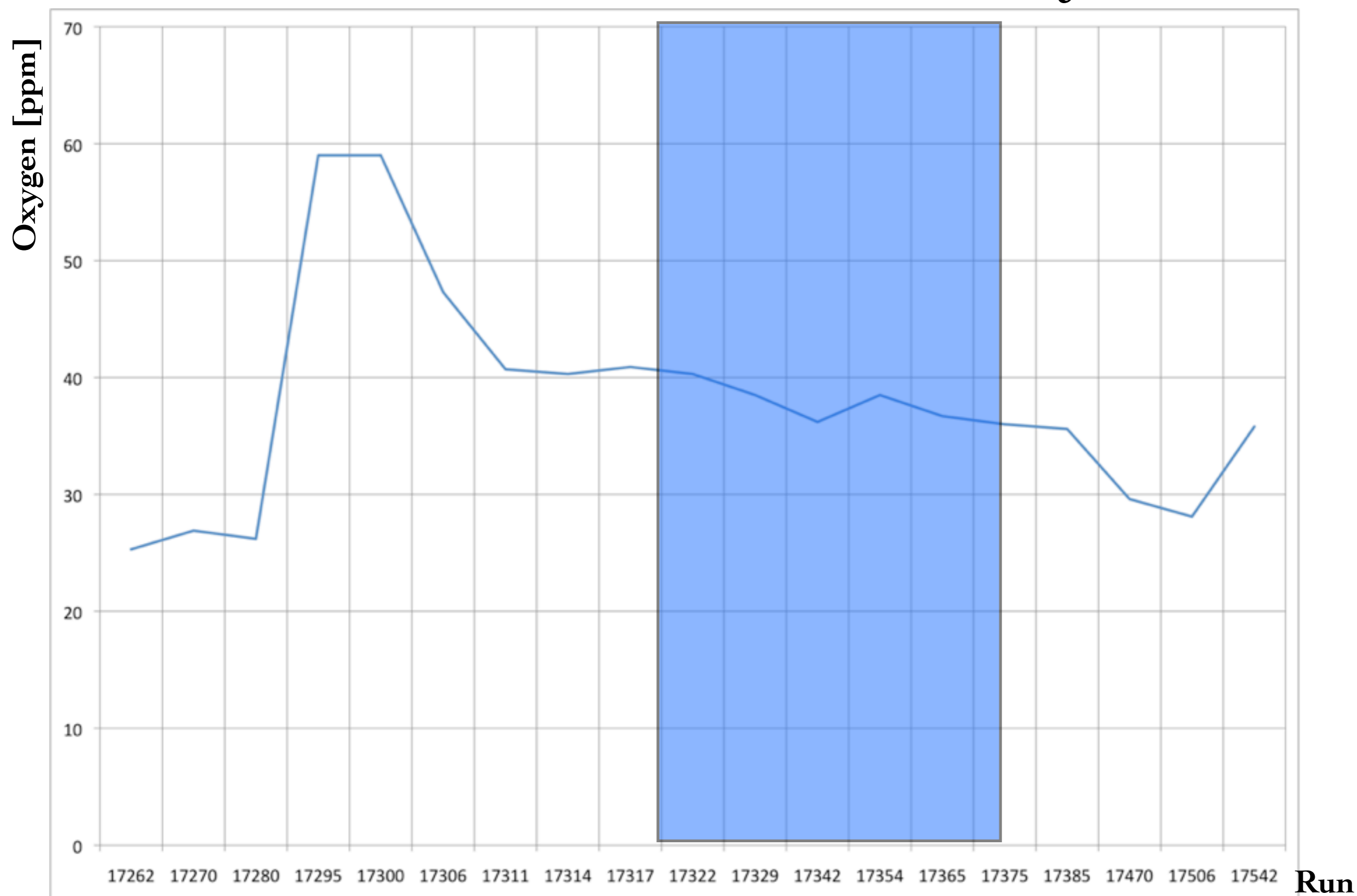


Oxygen could be the cause ?

(a) and (b) can be good samples to check the oxygen effect.

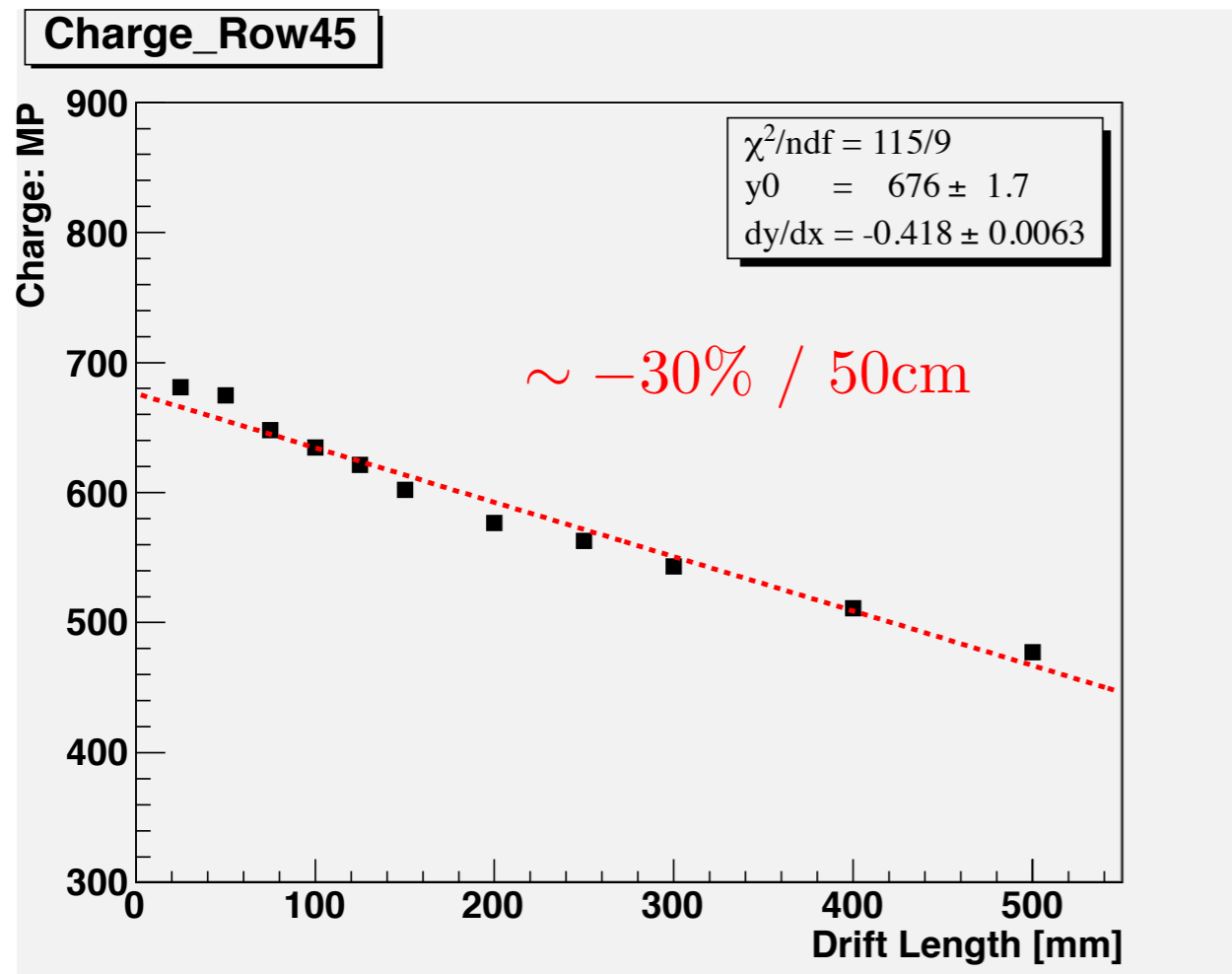
# 2010 Oxygen data

The runs we analyzed.

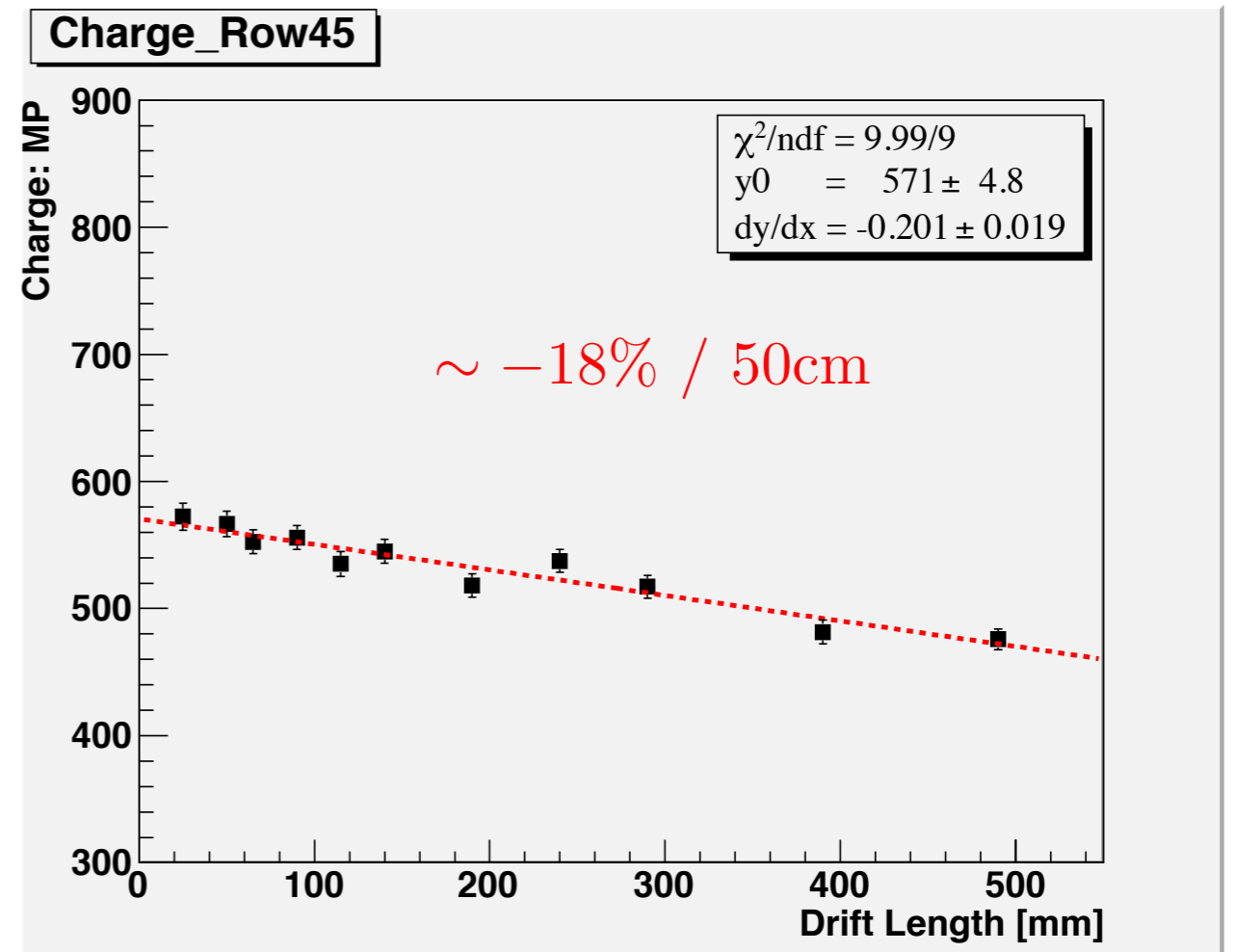


# charge by row

## B=1T

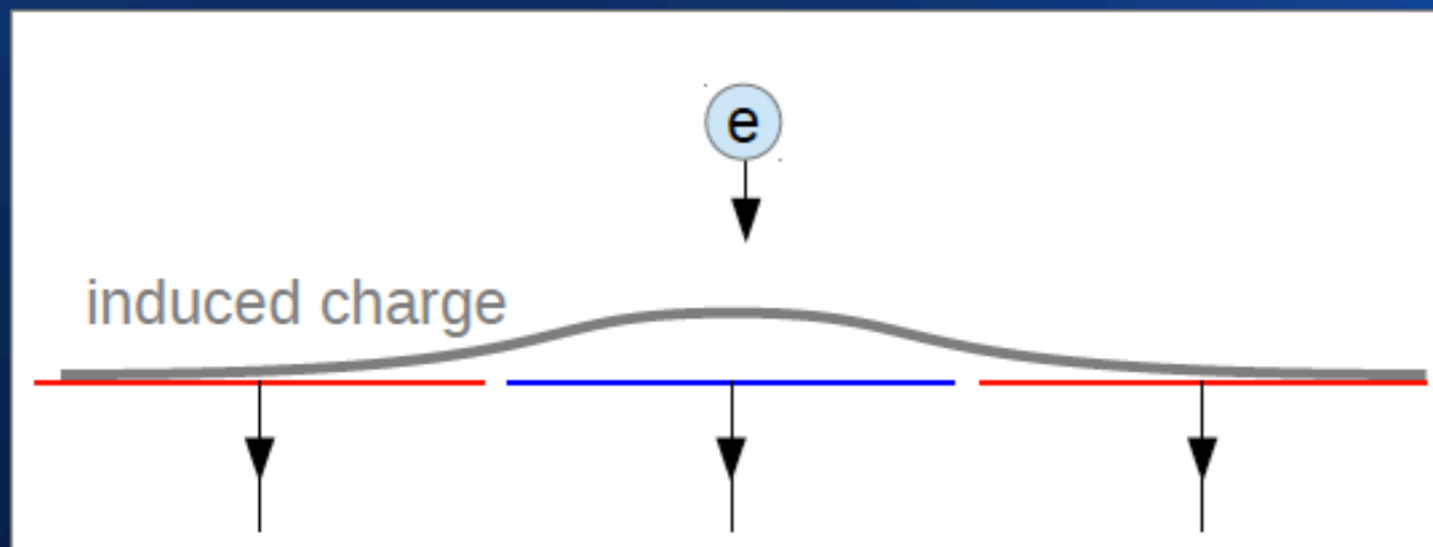


## B=0T



# Likely explanation: Induction on neighbour pad

When an electron reaches the pad, it induces a signal in the neighbour pads  
The induced signal appears to be ahead of the main signal



The induced signal arrives  
"before" the real one

